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Braunmuller, B.; Ester, M.; Kriegel, H.-P.; Sander, J.;
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Paul, R.A.; Kunii, T.L.; Shinagawa, Y.; Ghafoor, A.;
Computer Software and Applications Conference, 1997. COMPSAC '97. Proce
Twenty-First Annual International
13-15 Aug. 1997 Page(s):32 - 37
Digital Object Identifier 10.1109/CMPSAC.1997.624730

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Andersson, T.; Eriksson, I.; Amoroso, D.L.;
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Volume iv, 7-10 Jan. 1992 Page(s):348 - 358 vol.4
Digital Object Identifier 10.1109/HICSS.1992.183364

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Abran, A.;
Software Engineering Standards Symposium and Forum, 1997. 'Emerging Inte
Standards'. ISESS 97., Third IEEE International
1-6 June 1997 Page(s):275 - 277

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7. **Software metrics knowledge and databases for project management**
Paul, R.A.; Kunii, T.L.; Shinagawa, Y.; Khan, M.F.;
Knowledge and Data Engineering, IEEE Transactions on
Volume 11, Issue 1, Jan.-Feb. 1999 Page(s):255 - 264
Digital Object Identifier 10.1109/69.755633

AbstractPlus | References | Full Text: PDF(344 KB)   IEEE JNL
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8. **Fast indexing and visualization of metric data sets using slim-trees**
Traina, C., Jr.; Traina, A.; Faloutsos, C.; Seeger, B.;
Knowledge and Data Engineering, IEEE Transactions on
Volume 14, Issue 2, March-April 2002 Page(s):244 - 260
Digital Object Identifier 10.1109/69.991715

AbstractPlus | References | Full Text: PDF(1530 KB)   IEEE JNL
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Sharpe, J.L.; Cangussu, J.W.;
Computer Software and Applications Conference, 2005. COMPSAC 2005. 29tl
International
Volume 1, 26-28 July 2005 Page(s):59 - 64 Vol. 2
Digital Object Identifier 10.1109/COMPSAC.2005.31

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Chavez, E.; Herrera, N.; Reyes, N.;
Computer Science Society, 2004. SCCC 2004. 24th International Conference
11-12 Nov. 2004 Page(s):121 - 129
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   IEEE JNL

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   IEEE JNL

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   IEEE CNF

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   IEEE CNF   *Considered.*

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   1-6 June 1997 Page(s):275 - 277
   IEEE CNF

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   IEEE JNL

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IEEE JNL

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